Date of Issue: September 06, 2005

## **CE EMC**

## **TEST REPORT**

For

Micro ATX Board

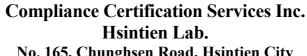
Model: EMB-900M

**Trade Name: AAEON** 

Issued to

AAEON Technology Inc. 5F, No.135, Lane 235, Pao Chiao Rd., Hsin-Tien City, Taipei, Taiwan, R.O.C.

Issued by





No. 165, Chunghsen Road, Hsintien City Taipei Hsien, Taiwan TEL: (02) 2217-0894

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### 1 TEST RESULT CERTIFICATION

Applicant: AAEON Technology Inc.

5F, No.135, Lane 235, Pao Chiao Rd., Hsin-Tien City,

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Taipei, Taiwan, R.O.C.

Manufacturer: AAEON Technology Inc.

5F, No.135, Lane 235, Pao Chiao Rd., Hsin-Tien City,

Taipei, Taiwan, R.O.C.

**Equipment Under Test:** 

Micro ATX Board

**Trade Name:** 

**AAEON** 

**Model:** 

EMB-900M

**Detailed EUT Description:** 

See Item 2 of this report

**Date of Test:** 

August 17, 2005 ~ September 04, 2005

Applicable Standard	Class/Limit/Criterion	Test Result		
EN 55022: 1998 + A1: 2000 + A2: 2003	Class A	No non-compliance noted		
EN 61000-3-2: 2000	Class A	No non-compliance noted		
EN 61000-3-3: 1995 + A1: 2001	Limit	No non-compliance noted		
EN 55024:1998 + A1: 2001 + A2: 2003, including	ng			
IEC 61000-4-2: 1995 + A1: 1998 + A2: 2000	Criterion B	No non-compliance noted		
IEC 61000-4-3: 2002 + A1: 2002	Criterion A	No non-compliance noted		
IEC 61000-4-4: 1995 + A1: 2000 + A2: 2001	Criterion B	No non-compliance noted		
IEC 61000-4-5: 1995 + A1: 2000	Criterion B	No non-compliance noted		
IEC 61000-4-6: 1996 + A1: 2000	Criterion A	No non-compliance noted		
IEC 61000-4-8: 1993 + A1: 2000	Criterion A	N/A		
IEC 61000-4-11: 1994 + A1: 2000	Criterion B/C/C	No non-compliance noted		
Deviation from Applicable Standard				
At the customers' request, we adopt the above standards.				

The above equipment was tested by Compliance Certification Services Inc. for compliance with the requirements set forth in the EMC Directive 89/336/EMC and the technical standards mentioned above. The results of testing in this report apply only to the product/system, which was tested. Other similar equipment will not necessarily produce the same results due to production tolerance and measurement uncertainties.

Approved by:

Reviewed by:

David Wang

Manager of Hsintien Laboratory

Compliance Certification Services Inc.

Vince Chiang

Assistant Manager of Hsintien Laboratory Compliance Certification Services Inc.

# 2 EUT DESCRIPTION

Product	Micro ATX Board	
Trade Name	AAEON	
Model	EMB-900M	
Housing Type	N/A	
Power Adaptor Power Rating	3.3VDC/ 5VDC/ ±12VDC from Host PC	
AC Power During Test	230VAC / 50Hz to Host PC Power Supply	
Power Supply Manufacturer	Seventeam	
Power Supply Model Number	ST-300BLV	
AC Power Cord Type	Unshielded, 1.8m (Detachable) to Host PC Power Supply	
OSC/Clock Frequencies	32.768kHz; 14.31818MHz; 25MHz	

### I/O PORT OF EUT

I/O PORT TYPE	Q'TY	TESTED WITH
1). PIO Port	1	1
2). PS/2 Keyboard Port	1	1
3). PS/2 Mouse Port	1	1
4). Video-Out Port (DVI)	1	1
5). Audio In Port	1	1
6). Microphone Port	1	1
7). Earphone Port	4	4
8). LAN Port	2	2
9). USB Port	4	4
10). OPTICAL FIBER Port	2	2

 $\it Note: Client consigns only one model sample (Model Number is EMB-900M) to test.$ 

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# 3 TEST METHODOLOGY

#### 3.1 EUT SYSTEM OPERATION

- 1. Windows XP boots system.
- 2. Run Emctest.exe to activate all peripherals and display "H" pattern on monitor screen.

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- 3. Run Winemc.exe and choose media player to play music.
- 4. Run Winemc.exe and choose "F:/ & G:/ & H:/ & I:/ & J:/ & K:/ & L:/ & I:/" to test USB 2.0 Port.
- 5. Press the start menu, select executive and type ping 192.168.0.2 –t (EUT), ping 192.168.0.1 –t (Server Notebook).

Note: Test program is self-repeating throughout the test.

#### 3.2 DECISION OF FINAL TEST MODE

1. The following test mode(s) were scanned during the preliminary test:

#### Mode:

#### 1. DVI TO D-SUB MODE

2. After the preliminary scan, the following test mode(s) was found to produce the highest emission level.

**Conduction:** Mode 1

**Radiation:** Mode 1

Then, the EUT configuration and cable configuration of the above highest emission mode was chosen for all final test items.

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# 4 SETUP OF EQUIPMENT UNDER TEST

## Setup Diagram

See test photographs attached in Appendix I for the actual connections between EUT and support equipment.

# **Support Equipment**

#### **Host PC Devices:**

No	Equipment	Model #	Trade Name
1.	CPU (3.20GHz)	Pentium4	Intel
2.	Memory (512MBX2)	DDR2-533	ELPIDA
3.	Power Supply	ST-300BLV	Seventeam
4.	HDD	2F040L0	Maxtor
5.	CD-ROM	CDU5211	SONY

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## **Peripherals Devices:**

No	Equipment	Model	Serial No.	FCC ID / BSMI ID	Trade Name	Data Cable	Power Cord
1.	USB 2.0 HDD	F12-U	N/A	BSMI ID: 4912A002	TeraSys	Shielded, 2.0m	N/A
2.	USB 2.0 HDD	F12-U	N/A	BSMI ID: 4912A002	TeraSys	Shielded, 2.0m	N/A
3.	USB 2.0 HDD	F12-U	N/A	BSMI ID: 4912A002	TeraSys	Shielded, 2.0m	N/A
4.	USB 2.0 HDD	F12-U	N/A	BSMI ID: 4912A002	TeraSys	Shielded, 2.0m	N/A
5.	PS/2 Mouse	M071KC	443029438	DoC BSMI: R41108	DELL	Shielded, 1.8m	N/A
6.	PS/2 Keyboard	SK-8110	N/A	DoC BSMI: T3A002	DELL	Shielded, 1.8m	N/A
7.	Ear. / Mic.	MSB301	N/A	N/A	e-Sense	Unshielded, 1.8m	N/A
8.	Player	RQ-L11LT	N/A	BSMI ID: 3912A162	Panasonic	Unshielded, 1.0m	N/A
9.	Earphone	MSB301	N/A	N/A	e-Sense	Unshielded, 1.8m	N/A
10.	USB 2.0 HDD	F12-U	N/A	BSMI ID: 4912A002	TeraSys	Shielded, 2.0m	N/A
11.	USB 2.0 HDD	F12-U	N/A	BSMI ID: 4912A002	TeraSys	Shielded, 2.0m	N/A
12.	USB 2.0 HDD	F12-U	N/A	BSMI ID: 4912A002	TeraSys	Shielded, 2.0m	N/A
13.	USB 2.0 HDD	F12-U	N/A	BSMI ID: 4912A002	TeraSys	Shielded, 2.0m	N/A
14.	Earphone	MSB301	N/A	N/A	e-Sense	Unshielded, 1.8m	N/A
15.	Earphone	MSB301	N/A	N/A	e-Sense	Unshielded, 1.8m	N/A
16.	Modem	5JEG4033MKO	N/A	5RJTAI-35500-M5-E	TOP- SOLUTION	Shielded, 1.8m	Unshielded, 1.8m
17.	Modem	5JEG4033MKO	N/A	5RJTAI-35500-M5-E	TOP- SOLUTION	Shielded, 1.8m	Unshielded, 1.8m
18.	Modem	1414	N/A	IFAXDM1414	ACEEX	Shielded, 1.8m	Unshielded, 1.8m
19.	Modem	5JEG4033MKO	N/A	5RJTAI-35500-M5-E	TOP- SOLUTION	Shielded, 1.8m	Unshielded, 1.8m
20.	Monitor	GH17PS	GH17H4LT604715L	DoC BSMI ID: 3902B332	SAMSUNG	Shielded, 1.8m with two cores	Unshielded, 1.8m
21.	Printer	C20SX	N/A	BSMI ID: 3902E004	EPSON	Shielded, 1.8m	Unshielded, 1.8m
22.	Server Notebook	PP05L	2464936188	DoC BSMI: R33002	DELL	Unshielded, 20m	Unshielded, 1.8m with a core

**Note:** All the above equipment/cables were placed in worse case positions to maximize emission signals during emission test.

**Grounding:** Grounding was in accordance with the manufacturer's requirements and conditions for the intended use.

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## 5 FACILITIES AND ACCREDITATIONS

#### **5.1 FACILITIES**

All measurement facilities used to collect the measurement data are located at CCS Taiwan Hsintien Lab at No. 165, Chunghsen Road, Hsintien City, Taipei Hsien, Taiwan.

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The measurement facilities are constructed in conformance with the requirements of CISPR 16-1, ANSI C63.4 and other equivalent standards.

#### 5.2 LABORATORY ACCREDITATIONS AND LISTINGS

The test facilities used to perform Electromagnetic compatibility tests are registered or accredited by the organizations listed in the following table which includes the recognized scope specifically.

Country	Agency	Scope of Accreditation	Logo
USA	A2LA	CFR 47, FCC Part 15/18 using ANSI 63.4; AS/NZS 3548; VCCI V3; CNS 13438; CNS 13439; CNS 13783; CNS 14115; CISPR 11/EN 55011; CISPR 14-1/EN 55014-1; CISPR 15/EN 55015; CISPR 22/EN 55022; EN 50081-1/EN 61000-6-3; EN 50082-1/EN 61000-6-4; IEC/EN 61000-4-2, IEC/EN 61000-4-3, IEC/EN 61000-4-4, IEC/EN 61000-4-5, IEC/EN 61000-4-6, IEC/EN 61000-4-8, IEC/EN 61000-4-11, IEC/EN 61000-3-2, IEC/EN 61000-3-3; CISPR 24/EN 55024; CISPR 14-2/EN 55014-2; EN 50081-2/EN 61000-6-1; EN 50082-2/EN 61000-6-2.	ACCREDITED 824.01
USA	FCC	3/10 meter Open Area Test Sites to perform FCC Part 15/18 measurements	<b>FC</b> 250366
Japan	VCCI	3/10 meter Open Area Test Sites and Line Conducted Test Room to perform conducted/radiated measurements	VCCI R-1434/1630~4 C-1511/1882
Norway	NEMKO	EN 50081-1/2, EN 50082-1/2, IEC 61000-6-1/2/3/4, EN 50091-2, EN 50130-4, EN 55011, EN 55013, EN 55014-1/2, EN 55015, EN 55022, EN 55024, EN 61000-3-2/3, EN 61326-1, IEC 61000-4-2/3/4/5/6/8/11, Cispr 16-1/2/3/4	ELA 103
Taiwan	CNLA	47 CFR FCC Part 15 Subpart B, EN 61000-3-2, EN 61000-3-3, CNS 13439, CNS 13783-1, CNS 13438, AS/NZS 3548, VCCI, CNS 13022-1/2/3, EN 55022, EN 55013, EN 55014-1, EN 61000-4-2/3/4/5/6/8/11, ENV 50204, ENV 50141, ENV 50142	1108 ILAC MRA
Taiwan	BSMI	CNS 13438, CNS 13783-1, CNS 13439	SL2-IN-E-0005 SL2-A1-E-0005 SL2-R1-E-0005 SL2-R2-E-0005
Canada	Industry Canada	RSS212, Issue 1	Canada IC 5742

**Note:** No part of this report may be used to claim or imply product endorsement by CNLA, A2LA or other government agency.

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### **6 INSTRUMENT AND CALIBRATION**

#### 6.1 MEASURING INSTRUMENT CALIBRATION

The measuring equipment utilized to perform the tests documented in this report has been calibrated once a year or in accordance with the manufacturer's recommendations, and is traceable to recognized national standards.

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## 6.2 TEST AND MEASUREMENT EQUIPMENT

The following list contains measurement equipment used for testing. The equipment conforms to the requirement of CISPR 16-1, ANSI C63.2 and. other required standards.

Calibration of all test and measurement, including any accessories that may effect such calibration, is checked frequently to ensure the accuracy. Adjustments are made and correction factors are applied in accordance with the instructions contained in the respective manual.

#### **Equipment Used for Emission Measurement**

Open Area Test Site # I					
EQUIPMENT	MFR	MODEL	SERIAL NUMBER	CAL. DUE	
SITE NSA	CCS	I Site	N/A	09/17/2005	
MEASURE RECEIVER	SCHAFFNER	SCR3501	338	06/27/2006	
SPECTRUM ANALYZER	ADVANTEST	R3132	120900008	No Calibration Required	
ANTENNA	SCHAFFNER	CBL 6112B	2809	09/24/2005	
AMPLIFIER	MCL	ZKL-1R5	6511600436	03/06/2006	
CABLE	SUHNER	RG 214	N-TYPE #Q2	02/18/2006	
THERMO- HYGRO METER	TFA	N/A	NO.2	11/09/2005	
DECOUPLING NETWORK	FCC	F-201-DCN-5-6MM	22 \ 24	08/24/2006	

**Note:** The measurement uncertainty is less than +/- 3.36dB, which is evaluated as per the NAMAS NIS 81 and CISPR/A/291/CDV.

Conducted Emission Test Site # A					
EQUIPMENT	MFR	MODEL	SERIAL NUMBER	CAL. DUE	
TEST RECEIVER	R&S	ESHS20	840455/006	02/17/2006	
LISN (EUT)	SCHWARZBECK	NSLK 8127	8127382	01/03/2006	
LISN	SOLAR	8012-50-R-24-BNC	8305114	01/03/2006	
BNC CABLE	MIYAZAKI	5D-FB	BNC A1	01/28/2006	
THERMO- HYGRO METER	ТОР	HA-202	9303-1	03/02/2006	
ISN	FCC	FCC-TLISN-T4	20166	07/13/2006	
ISN	FCC	FCC-TLISN-T8-02	20169	07/13/2006	

**Note:** The measurement uncertainty is less than +/- 2.83dB, which is evaluated as per the NAMAS NIS 81 and CISPR/A/291/CDV.

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Power Harmonic & Voltage Fluctuation/Flicker Test Site (EN 61000-3-2&-3-3)					
Manufacturer/Type Model No. Serial No.			Cal. Due		
Schaffner / Signal Conditioning Unit	CCN 1000-1	72122	12/05/2005		
Schaffner / 5KVA AC Power Source	NSG 1007	55131	No Calibration Required		

# **Equipment Used for Immunity Measurement**

ESD Test Site (EN 61000-4-2)				
Manufacturer/Type	Cal. Due			
Schaffner / ESD Simulator	NSG 438	129	04/20/2006	
Sato / Aneroid Barometer	7610-20	89090	09/07/2005	
TOP / Thermo-Hygro meter	HA-202	9303-1	03/02/2006	

Radiated Electromagnetic Field Immunity Test Site (EN 61000-4-3)					
Manufacturer/Type	Model No.	Serial No.	Cal. Due		
Calibration of Field	Chamber#RS	RS3H-7 / RS3V-7	07/01/2006		
Agilent / Signal Generator	E4421B	MY43350597	05/16/2006		
AR / Electric Field Probe	FP6001	305650	02/03/2006		
Boonton / RF Voltmeter	9200B	328001AE	02/23/2006		
BNC / Function Generator	625A	25451	02/17/2006		
AR / Amplifier	100W1000M1	17564	No Calibration Required		
Werlatone Inc. / Direction Coupler	C2630	4121	No Calibration Required		
Frankonia / Broadband Antenna	BTA-M	030001M	No Calibration Required		
TOP / Thermo-Hygro meter	HA-202	9303-2	03/02/2006		

Fast Transients/Burst Test Site (EN 61000-4-4)						
Manufacturer/Type	Model No.	Serial No.	Cal. Due			
Schaffner / EFT Generator	BEST EMC V2.3	200031A024SC	11/09/2005			
Schaffner / Capacitive Clamp	N/A	N/A	No Calibration Required			

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Surge Immunity Test Site (EN 61000-4-5)						
Manufacturer/Type Model No. Serial No. Cal. Due						
Schaffner / Surger Generator	BEST EMC V2.3	200031A024SC	11/09/2005			
Schaffner / Signal and Data Lines Coupling Network	CDN118	19328	No Calibration Required			

CS test (EN 61000-4-6)					
Manufacturer/Type	Model No.	Serial No.	Cal. Due		
Schaffner / RF Generator	NSG 2070-1	1061	08/03/2006		
Schaffner / CDN	CDN M316	19600	08/02/2006		
Schaffner / CDN	CDN M216	19294	08/02/2006		
FCC / CDN	FCC-801-M3-16A	99122	08/02/2006		
Schaffner / EM Clamp	KEMZ 801	19227	02/23/2006		
Schaffner / CDN	CDN T002	CDN T002 15881			
FCC / CDN	FCC-801-T8-RJ45 04025		06/23/2006		
Schaffner / Attenuator	INA2070-1	2061	No Calibration Required		
FCC / CDN	FCC-801-T4-RJ45 04031		08/02/2006		

Power Frequency Magnetic Field Immunity test (EN 61000-4-8)						
Manufacturer/Type	Model No.	Serial No.	Cal. Due			
Schaffner / Induction Coil Interface	oil Interface INA 21141 600		No Calibration Required			
Schaffner / 5KVA AC Power Source	NSG 1007	55131	No Calibration Required			
CHY/ TRMS Clamp Meter	932C	2K0900285	10/12/2005			
Sypris / Magnetic Field Meter	4080	0247	01/19/2006			

Voltage Dips/Short Interruption and Voltage Variation Immunity test (EN 61000-4-11)								
Manufacturer/Type Model No. Serial No. Cal. D								
Schaffner / Dips/Interruption/Variations Tester	BEST EMC V2.3	200031A024SC	11/09/2005					
Protronix / Digital Power Meter	1201	201091	08/24/2006					

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# 7 LINE CONDUCTED & RADIATED EMISSION TEST

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#### **7.1 LIMIT**

### **Maximum permissible level of Line Conducted Emission**

FREQUENCY	Class A (	(dBuV)	Class B (dBuV)		
(MHz)	Quasi-peak Average		Quasi-peak	Average	
0.15 - 0.5	79	66	66 - 56	56 - 46	
0.50 - 5.0	73	60	56	46	
5.0 - 30.0	73	60	60	50	

*Note:* The lower limit shall apply at the transition frequency.

## <u>Maximum permissible level of Common Mode Conducted Emission</u> (<u>Telecommunication Ports</u>)

#### **CLASS A**

FREQUENCY	Voltage Limit (dBuV)		Current Limit (dBuA)		
(MHz)	Quasi-peak Average		Quasi-peak	Average	
0.15 - 0.5	97 – 87	84 - 74	53 – 43	40 – 30	
0.5 - 30.0	87	74	43	30	

#### **CLASS B**

FREQUENCY	Voltage Limit (dBuV)		Current Limit (dBuA)		
(MHz)	Quasi-peak Average		Quasi-peak	Average	
0.15 - 0.5	84 - 74	74 - 64	40 – 30	30 – 20	
0.5 - 30.0	74	64	30	20	

*Note:* The lower limit shall apply at the transition frequency.

#### Maximum permissible level of Radiated Emission measured at 10 meter

FREQUENCY	Class A (dBuV/m)	Class B (dBuV/m)	
(MHz)	Quasi-peak	Quasi-peak	
30 – 230	40	30	
230 - 1000	47	37	

*Note:* The lower limit shall apply at the transition frequency.

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#### 7.2 TEST PROCEDURE OF LINE CONDUCTED EMISSION

#### **Procedure of Preliminary Test**

• The EUT was set up as per the test configuration to simulate typical usage per the user's manual. When the EUT is a tabletop system, a wooden table with a height of 0.8 meters is used and is placed on the ground plane as per EN 55022 (see Test Facility for the dimensions of the ground plane used). When the EUT is a floor-standing equipment, it is placed on the ground plane which has a 3-12 mm non-conductive covering to insulate the EUT from the ground plane.

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- Support equipment, if needed, was placed as per EN 55022.
- All I/O cables were positioned to simulate typical actual usage as per EN 55022.
- The test system with EUT received AC power, 230V/50Hz, through a Line Impedance Stabilization Network (LISN), which supplied power source and was grounded to the ground plane.
- All support equipment received power from a second LISN.
- The EUT test program was started. Emissions were measured on each current carrying line of the EUT using an EMI Test Receiver connected to the LISN powering the EUT.
- The Receiver scanned from 150kHz to 30MHz for emissions in each of the test modes.
- During the above scans, the emissions were maximized by cable manipulation.
- The test mode(s) described in Item 3.2 were scanned during the preliminary test.
- After the preliminary scan, we found the test mode described in Item 3.2 producing the highest emission level.
- The EUT configuration and cable configuration of the above highest emission level were recorded for reference of the final test.

#### **Procedure of Final Test**

- EUT and support equipment were set up on the test bench as per the configuration with highest emission level in the preliminary test.
- A scan was taken on both power lines, Line 1 and Line 2, recording at least the six highest emissions. Emission frequency and amplitude were recorded into a computer in which correction factors were used to calculate the emission level and compare reading to the applicable limit. If EUT emission level was less –2dB to the Average limit in Q.P. mode, then the emission signal was re-checked using an Average detector.
- The test data of the worst-case condition(s) was recorded.

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#### **Data Sample:**

Freq. MHz	Read Level dBuV	Factor dB	Level dBuV	Limit dBuV	Over Limit dB	Reading Type (P/Q/A)	Line (L1/L2)
X.XX	42.95	0.55	43.50	73	-29.50	Q	L1

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Freq. = Emission frequency in MHz

Read Level = Uncorrected Analyzer/Receiver reading Factor = Insertion loss of LISN + Cable Loss

Level = Read Level + Factor Limit = Limit stated in standard Over Limit = Reading in reference to limit

P = Peak Reading

Q = Quasi-peak Reading A = Average Reading

L1 = Hot side L2 = Neutral side

#### **Calculation Formula**

Over Limit (dB) = Level (dBuV) – Limit (dBuV)

# 7.3 TEST PROCEDURE OF COMMON MODE CONDUCTED EMISSION FOR TELECOMMUNICATION PORT

- Selecting ISN for unscreened cable or a current probe for screened cable to take measurement.
- The port of the EUT was connected to the remote side support equipment through the ISN/Current Probe and communication in normal condition.
- Making a overall range scan by using the test receiver controlled by controller and record at least six highest emissions for showing in the test report.
- Emission frequency and amplitude were recorded into a computer in which correction factors were used to calculate the emission level and compare reading to the applicable limit.
- In case of measuring on the screened cable, the current limit shall be applied, otherwise the voltage limit should be applied.
- The following test mode(s) were scanned during the preliminary test:

#### Mode(s):

1.	LAN 1	1Gbps
2.		10 Mbps
3.	LAN 2	100 Mbps
4.		1Gbps

• After the preliminary scan, we found the following test mode(s) producing the highest emission level and test data of the worst case was recorded.

#### Mode 4.

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#### **Data Sample:**

Freq. MHz	Read Level dBuV	Factor dB	Level dBuV	Limit dBuV	Over Limit dB	Reading Type (P/Q/A)
X.XX	62.95	0.55	63.50	87	-23.50	Q

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Freq. = Emission frequency in MHz

Read Level = Uncorrected Analyzer/Receiver reading

Factor = Insertion loss of ISN + Cable Loss

Level = Read Level + Factor Limit = Limit stated in standard Over Limit = Reading in reference to limit

P = Peak Reading

Q = Quasi-peak Reading A = Average Reading

#### **Calculation Formula**

Over Limit (dB) = Level (dBuV) – Limit (dBuV)

#### 7.4 TEST PROCEDURE OF RADIATED EMISSION

#### **Procedure of Preliminary Test**

- The equipment was set up as per the test configuration to simulate typical usage per the user's manual. When the EUT is a tabletop system, a wooden turntable with a height of 0.8 meters is used which is placed on the ground plane. When the EUT is a floor-standing equipment, it is placed on the ground plane which has a 3-12 mm non-conductive covering to insulate the EUT from the ground plane.
  - Support equipment, if needed, was placed as per EN 55022.
  - All I/O cables were positioned to simulate typical usage as per EN 55022.
  - The EUT received AC power source, 230V/50Hz, from the outlet socket under the turntable. All support equipment received power from another socket under the turntable.
  - Mains cables, telephone lines or other connections to auxiliary equipment located outside the test are shall drape to the floor, be fitted with ferrite clamps or ferrite tubes placed on the floor at the point where the cable reaches the floor and then routed to the place where they leave the turntable. No. extension cords shall be used to mains receptacle.
  - The antenna was placed at 10 meter away from the EUT as stated in EN 55022. The antenna connected to the Spectrum Analyzer via a cable and at times a pre-amplifier would be used.
  - The Analyzer / Receiver quickly scanned from 30MHz to 1000MHz. The EUT test program was started. Emissions were scanned and measured rotating the EUT to 360 degrees and positioning the antenna 1 to 4 meters above the ground plane, in both the vertical and the horizontal polarization, to maximize the emission reading level.

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- The test mode(s) described in Item 3.2 were scanned during the preliminary test:
- After the preliminary scan, we found the test mode described in Item 3.2 producing the highest emission level.
- The EUT and cable configuration, antenna position, polarization and turntable position of the above highest emission level were recorded for the final test.

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#### **Procedure of Final Test**

- EUT and support equipment were set up on the turntable as per the configuration with highest emission level in the preliminary test.
- The Analyzer / Receiver scanned from 30MHz to 1000MHz. Emissions were scanned and measured rotating the EUT to 360 degrees, varying cable placement and positioning the antenna 1 to 4 meters above the ground plane, in both the vertical and the horizontal polarization, to maximize the emission reading level.
- Recorded at least the six highest emissions. Emission frequency, amplitude, antenna position, polarization and turntable position were recorded into a computer in which correction factors were used to calculate the emission level and compare reading to the applicable limit and only Q.P. reading is presented.

### **Data Sample:**

Freq. MHz	Read Level dBuV	Factor dB/m	Level dBuV/m	Limit dBuV/m	Over Limit dB	Reading Type (P/Q/A)	Pol. (H/V)
X.XX	14.0	12.2	26.2	40	-13.8	Q	Н

Freq. = Emission frequency in MHz

Read Level = Uncorrected Analyzer/Receiver reading

Factor = Antenna Factor + Cable Loss + Attenuator (3/6/10dB) – Amplifier Gain

Level = Read Level + Factor
Limit = Limit stated in standard
Over Limit = Reading in reference to limit

P = Peak Reading

Q = Quasi-peak Reading A = Average Reading

H = Antenna Polarization: Horizontal V = Antenna Polarization: Vertical

#### **Calculation Formula**

Over Limit (dB) = Level (dBuV/m) – Limit (dBuV/m)

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### 7.5 TEST RESULTS

#### **Line Conducted Emission**

Model: EMB-900M Test Mode: Mode 1

Temperature: 26°C Humidity: 46% RH

**Test Results:** Passed **Tested by:** Sam Su

(The chart below shows the highest readings taken from the final data, see **Appendix III** for details.)

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Six Highest Conducted Emission Readings								
Fre	quency Ran	ge Investiga	ated	150 kHz to 30 MHz				
Freq (MHz)	Read Level (dBuV)	Factor (dB)	Level (dBuV)	Limit Line (dBuV)	Over Limit (dB)	Reading Type (P/Q/A)	Line (L1/L2)	
0.171	72.03	0.14	72.17	79.00	-6.83	P	L1	
0.171	15.45	0.14	15.59	66.00	-50.41	A	L1	
0.224	72.03	0.15	72.18	79.00	-6.82	P	L1	
0.224	16.37	0.15	16.52	66.00	-49.48	A	L1	
0.260	67.29	0.17	67.46	79.00	-11.54	P	L1	
0.337	66.15	0.19	66.34	79.00	-12.66	P	L1	
0.510	62.48	0.20	62.68	73.00	-10.32	P	L1	
4.158	47.86	0.35	48.21	73.00	-24.79	P	L1	
4.158	46.97	0.40	47.37	73.00	-25.63	P	L2	

**NOTE:** The emission level was or more than 2dB below the Average limit, so no re-check anymore.

### **Common Mode Conducted Emission**

Six Highest Conducted Emission Readings							
Frequency Range Investigated				150 kHz to 30 MHz			
	Read				Limit	Over	Reading
Freq	Level	Factor	Le	vel	Line	Limit	Type
(MHz)	(dBuV)	(dB)	(dB	uV)	(dBuV)	(dB)	(P/Q/A)
0.201	55.43	9.77	65.	.20	94.58	-29.38	P
0.315	55.40	9.75	65.	.15	90.84	-25.69	P
0.419	57.44	9.75	67.	.19	88.46	-21.28	P
0.608	57.43	9.74	67.	.17	87.00	-19.83	P
0.871	55.65	9.74	65.	.39	87.00	-21.61	P
10.790	36.17	9.80	45.	.97	87.00	-41.03	P

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Test Mode: Mode 4

## **Radiated Emission**

Model: EMB-900M Test Mode: Mode 1

**Temperature:** 27°C **Humidity:** 45% RH

**Test Results:** Passed **Tested by:** Jimmy Chen

(The chart below shows the highest readings taken from the final data, see Appendix III for details.)

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Six Highest Radiated Emission Readings								
Fre	quency Ran	ge Investiga	ated	30 MHz to 1000 MHz at 10m				
	Read			Limit	Over	Reading		
Freq	Level	Factor	Level	Line	Limit	Type	Pol.	
(MHz)	(dBuV)	(dB/m)	(dBuV/m)	(dBuV/m)	(dB)	(P/Q/A)	(H/V)	
66.100	63.64	-26.89	36.75	40.00	-3.25	P	V	
75.530	61.24	-25.90	35.34	40.00	-4.66	P	V	
122.750	53.25	-19.83	33.42	40.00	-6.58	P	V	
166.000	56.96	-21.22	35.74	40.00	-4.26	P	V	
207.700	52.59	-20.90	31.69	40.00	-8.31	P	V	
122.740	54.34	-19.83	34.51	40.00	-5.49	P	Н	

NOTE: None.

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# **8 POWER HARMONICS TEST**

**Port** : AC Power Port

**Basic Standard** : EN 61000-3-2 (2000)

Limits : V CLASS A; CLASS D

**Tested by** : Mark Hsu

**Temperature** : 22°C **Humidity** : 58%

# **Limit:**

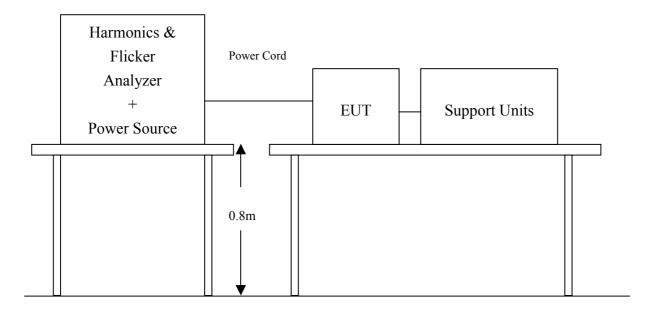
Limits for	Class A equipment		
Harmonics	Max. permissible		
Order	harmonics current		
n	A		
Od	d harmonics		
3	2.30		
5	1.14		
7	0.77		
9	0.40		
11	0.33		
13	0.21		
15<=n<=39	0.15x15/n		
Eve	en harmonics		
2	1.08		
4	0.43		
6	0.30		
8<=n<=40	0.23x8/n		

	Limits for Class D equipment						
Harmonics	Max. permissible harmonics	Max. permissible					
Order	current per watt mA/W	harmonics current					
n		A					
	Odd Harmonics only	I					
3	3.4	2.30					
5	1.9	1.14					
7	1.0	0.77					
9	0.5	0.40					
11	0.35	0.33					
13	0.30	0.21					
15<=n<=39	3.85/n	0.15x15/n					

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# **Block Diagram of Test Setup:**



## **Test Procedure:**

- a. The EUT was placed on the top of a wooden table 0.8 meters above the ground and operated to produce the maximum harmonic components under normal operating conditions for each successive harmonic component in turn.
- b. The correspondent test program of test instrument to measure the current harmonics emanated from EUT is chosen. The measure time shall be not less than the time necessary for the EUT to be exercised.

<u>Test Result</u>: (See Appendix II for details)

	<b>⊠</b> PASS	☐ FAIL	
Note: None.			

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# POWER VOLTAGE FLUCTUATION / FLICKER TEST

: AC Power Port **Port** 

**Basic Standard** : EN 61000-3-3 (1995 + A1: 2001)

Limits : §5 of EN 61000-3-3

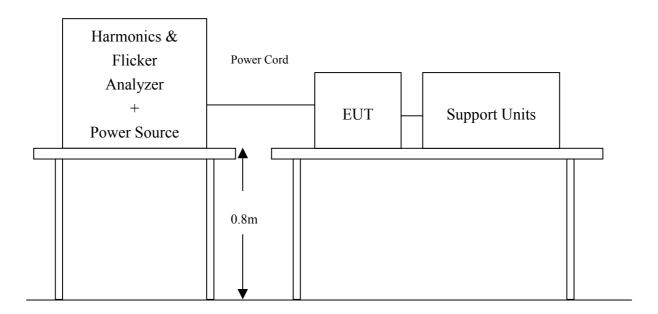
**Tested by** : Mark Hsu

: 22°C **Temperature** Humidity : 58%

# **Limit:**

TEST ITEM	LIMIT	REMARK
$P_{st}$	1.0	$P_{st}$ means short-term flicker indicator.
P <sub>lt</sub>	0.65	P <sub>lt</sub> means long-term flicker indicator.
T <sub>dt</sub> (ms)	500	T <sub>dt</sub> means maximum time that dt exceeds 3.3 %.
d <sub>max</sub> (%) 4%		d <sub>max</sub> means maximum relative voltage change.
dc (%)	3.3%	dc means relative steady-state voltage change

# **Block Diagram of Test Setup:**



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## **Test Procedure:**

a. The EUT was placed on the top of a wooden table 0.8 meters above the ground and operated to produce the most unfavorable sequence of voltage changes under normal operating conditions.

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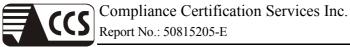
b. During the flick measurement, the measure time shall include that part of whole operation cycle in which the EUT produce the most unfavorable sequence of voltage changes. The observation period for short-term flicker indicator is 10 minutes and the observation period for long-term flicker indicator is 2 hours.

**Test Result:** (See Appendix II for details)

TEST PARAMETER	MEASUREMENT VALUE	LIMIT	RESULT
$P_{st}$	0.001	1.0	Pass
$P_{lt}$	0.001	0.65	Pass
T <sub>dt</sub> (ms)	0.0	500	Pass
d <sub>max</sub> (%)	0.00	4%	Pass
dc (%)	0.00	3.3%	Pass

**Observation:** None.

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# 10 ELECTROSTATIC DISCHARGE (ESD) IMMUNITY TEST

**Port** : Enclosure

**Basic Standard** : IEC/EN 61000-4-2

**Test Level** :  $\pm 8 \text{ kV}$  (Air Discharge)

± 4 kV (Contact Discharge)

± 4 kV (Indirect Discharge)

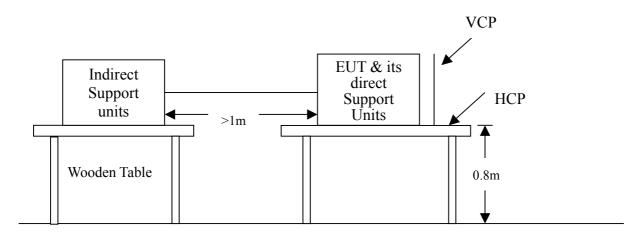
**Performance Criterion:** B (Standard Required)

**Tested by** : Mark Hsu

**Temperature** : 22°C : 58% Humidity : 1013mbar **Pressure** 

# **Block Diagram of Test Setup:**

(The 470 k ohm resistors are installed per standard requirement.)



Ground Reference Plane

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## **Test Procedure:**

- 1. The EUT was located 0.1 m minimum from all sides of the HCP.
- 2. The indirect support units were located 1 m minimum away from the EUT, but direct support unit was/were located at same location as EUT on the HCP and keep at a distance of 10 cm with EUT.

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- 3. As per the requirement of EN 55024; applying direct contact discharge at the sides other than front of EUT at minimum 50 discharges (25 positive and 25 negative) if applicable, can't be applied direct contact discharge side of EUT then the indirect discharge shall be applied. One of the test points shall be subjected to at least 50 indirect discharge (contact) to the front edge of horizontal coupling plane.
- 4. Other parts of EUT where it is not possible to perform contact discharge then selecting appropriate points of EUT for air discharge, a minimum of 10 single air discharges shall be applied.
- 5. The application of ESD to the contact of open connectors is not required.
- 6. The EUT direct connection units also need to be applied ESD at the port of EUT cable connected.
- 7. Putting a mark on EUT to show tested points. The following test condition was followed during the tests.

*Note:* As per IEC/EN 61000-4-2, two 470k bleed resistors cable is connected between the EUT and HCP during the test applicable for power ungrounded or battery operating unit only.

The electrostatic discharges were applied as follows:

Amount of discharge	Voltage	Coupling	Result (Pass/Fail)
Mini 10 /Point	$\pm 8 \text{ kV}$	Air Discharge	Pass
Mini 25 /Point	$\pm 4 \text{ kV}$	Contact Discharge	Pass
Mini 25 /Point	$\pm 4 \; kV$	Indirect Discharge HCP (Front)	Pass
Mini 25 /Point	$\pm 4 \; kV$	Indirect Discharge VCP (Right)	Pass
Mini 25 /Point	± 4 kV	Indirect Discharge VCP (Left)	Pass
Mini 25 /Point	± 4 kV	Indirect Discharge VCP (Back)	Pass

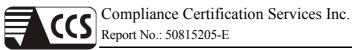
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# **Performance & Result:**

	Criterion A:	The apparatus continues to operate as intended. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance.
	Criterion B:	The apparatus continues to operate as intended after the test. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance. During the test, degradation of performance is however allowed.
	Criterion C:	Temporary loss of function is allowed, provided the functions self recoverable or can be restored by the operation of controls.
Oł	oservation:	No function degraded during the tests.

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# 11 RADIATED ELECTROMAGNETIC FIELD IMMUNITY **TEST**

**Port** : Enclosure

: IEC/EN 61000-4-3 **Basic Standard** 

**Requirements** : 3 V/m / with 80% AM. 1kHz Modulation.

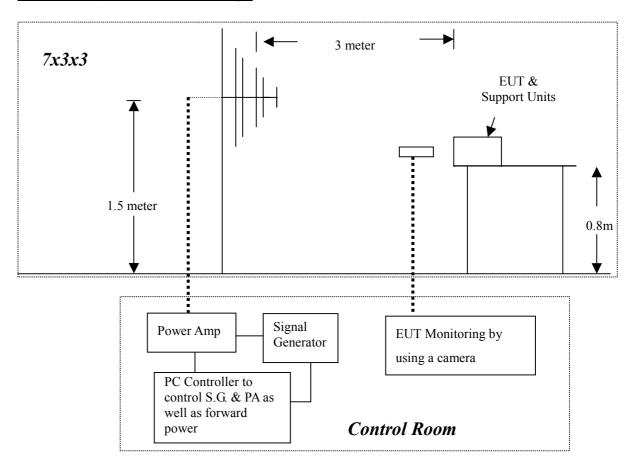
**Performance Criterion:** A (Standard Required)

: Mark Hsu **Tested by** 

: 22°C **Temperature** : 58% Humidity

**Pressure** : 1013mbar

# **Block Diagram of Test Setup:**



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# **Test Procedure:**

1. The EUT and support units were located at the edge of supporting table keep 3 meter away from transmitting antenna, it just the calibrated square area of field uniformity.

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- 2. Adjusting the cables to be exposed to the electromagnetic filed as possible.
- 3. Performing a Radiated Emission Scan in range of 80 to 1000 MHz prior to do RS test and records the more higher emission frequencies for the reference of RS test, due to antenna effectiveness.
- 4. Adjusting the monitoring camera to monitor the "H" message as clear as possible.
- 5. Setting the testing parameters of RS test software per IEC 61000-4-3.
- 6. Referring to the tested data of step 3 to performing the RS test from 80 to 1000 MHz.
- 7. Recording the test result in following table.
- 8. Changing the EUT to the other side and repeat step 3 to 6, until 4 sides of EUT were verified.

#### IEC 61000-4-3 Final test conditions:

Test level : 3V/m

Steps : 1 % of fundamental

Dwell Time: 3 sec

Range (MHz)	Field	Modulation	Polarity	Position (°)	Result (Pass/Fail)
80-1000	3V/m	Yes	Н	Front	Pass
80-1000	3V/m	Yes	V	Front	Pass
80-1000	3V/m	Yes	Н	Right	Pass
80-1000	3V/m	Yes	V	Right	Pass
80-1000	3V/m	Yes	Н	Back	Pass
80-1000	3V/m	Yes	V	Back	Pass
80-1000	3V/m	Yes	Н	Left	Pass
80-1000	3V/m	Yes	V	Left	Pass

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# **Performance & Result:**

	Criterion A:	The apparatus continues to operate as intended. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance.	
	Criterion B: The apparatus continues to operate as intended after the test. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replace by a permissible loss of performance. During the test, degradation of performance is however allowed.		
	Criterion C:	Temporary loss of function is allowed, provided the functions self recoverable or can be restored by the operation of controls.	
Oł	oservation:	No function degraded during the tests.	

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#### 12 FAST TRANSIENTS/BURST IMMUNITY TEST

Port : AC Power Port and RJ45 Port

**Basic Standard** : IEC/EN 61000-4-4

:  $\pm 1$  kV for AC Power Port Requirements

 $\pm$  0.5 kV for RJ45 Port

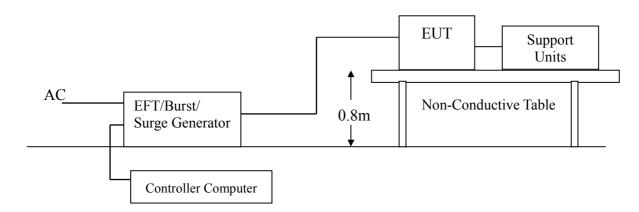
**Performance Criteria**: B (Standard Required)

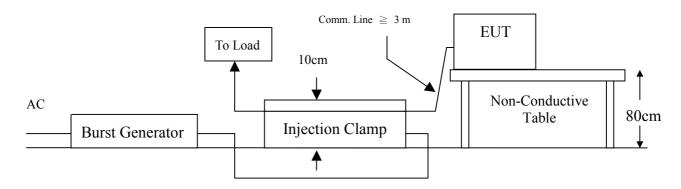
**Tested by** : Mark Hsu

: 22°C **Temperature** : 58% Humidity

**Pressure** : 1013mbar

## **Block Diagram of Test Setup:**





#### **Test Procedure:**

- 1. The EUT and support units were located on a wooden table 0.8 m away from ground reference plane.
- 2. A 1.0 meter long power cord was attached to EUT during the test.
- 3. The length of communication cable between communication port and clamp was keeping within 1 meter.
- 4. Injected test voltage to the EUT ports from minimum to standard request or client request.
- 5. Recorded the test result as shown in following table.

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### **Test conditions:**

Impulse Frequency: 5kHz
Tr/Th: 5/50ns
Burst Duration: 15ms
Burst Period: 300ms

Inject Line	Voltage kV	Inject Method	Result (Pass/Fail)
L	± 1	Direct	Pass
N	± 1	Direct	Pass
PE	± 1	Direct	Pass
L+N	± 1	Direct	Pass
L + PE	± 1	Direct	Pass
N + PE	± 1	Direct	Pass
L + N + PE	± 1	Direct	Pass
RJ45	± 0.5	Clamp	Pass

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# **Performance & Result:**

	Criterion A:	The apparatus continues to operate as intended. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance.
	Criterion B:	The apparatus continues to operate as intended after the test. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance. During the test, degradation of performance is however allowed.
	Criterion C:	Temporary loss of function is allowed, provided the functions self recoverable or can be restored by the operation of controls.
Ob	servation:	No function degraded during the tests.

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# 13 SURGE IMMUNITY TEST

Port : AC Power Port
Basic Standard : IEC/EN 61000-4-5

**Requirements** :  $\pm 1 \text{ kV}$  (Line to Line) for AC Power Port

± 2 kV (Line to Ground) for AC Power Port

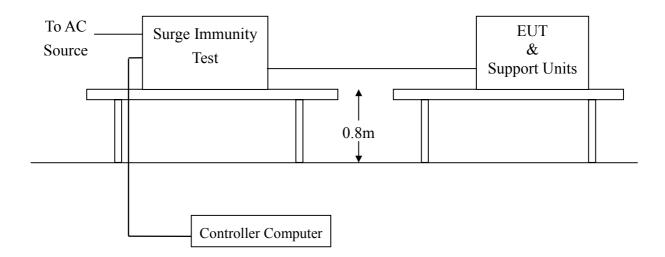
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**Performance Criteria**: B (Standard Required)

Tested by : Mark Hsu
Temperature : 22°C
Humidity : 58%

Pressure : 1013mbar

# **Block Diagram of Test Setup:**



### **Test Procedure:**

- 1. The EUT and support units were located on a wooden table 0.8 m away from ground floor.
- 2. Injected test voltage to the EUT ports from minimum to standard request or client request.
- 3. Recorded the test result as shown in following table.

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**Test conditions:** 

Voltage Waveform : 1.2/50 usCurrent Waveform : 8/20 us

Polarity : Positive/Negative Phase angle : 0°, 90°, 270°

Number of Test : 5

<b>Coupling Line</b>	Voltage (kV)	Polarity	Coupling Method	Result (Pass/Fail)
L1-L2	1	Positive	Capacitive	Pass
L1-PE	2	Positive	Capacitive	Pass
L2-PE	2	Positive	Capacitive	Pass
L1-L2	1	Negative	Capacitive	Pass
L1-PE	2	Negative	Capacitive	Pass
L2-PE	2	Negative	Capacitive	Pass

# **Performance & Result:**

	Criterion A:	The apparatus continues to operate as intended. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance.
	Criterion B:	The apparatus continues to operate as intended after the test. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance. During the test, degradation of performance is however allowed.
	Criterion C:	Temporary loss of function is allowed, provided the functions self recoverable or can be restored by the operation of controls.
Ob		Where normal functioning of LAN can't be achieved because of the impact of CDN on the EUT, no test be required.

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# 14 CONDUCTED DISTRBANCE/INDUCED RADIO-FREQUENCY FIELD IMMUNITY TEST

**Port** : AC Power Port and RJ45 Port

**Basic Standard**: IEC/EN 61000-4-6

**Requirements** : 3 V, with 80% AM. 1kHz Modulation.

**Injection Method** : CDN-M3 for AC Power Port

CDN-T4 & T8 for RJ45 Port

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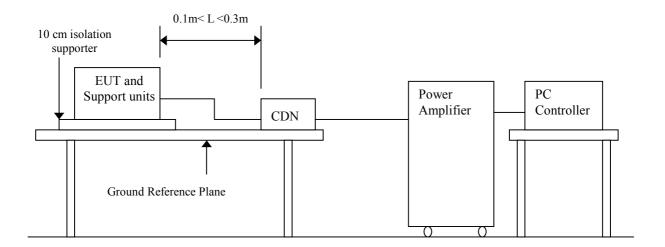
**Performance Criterion:** A (Standard Required)

**Tested by** : Mark Hsu

**Temperature** : 22°C **Humidity** : 58%

Pressure : 1013mbar

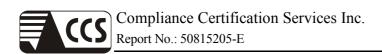
## **Block Diagram of Test Setup:**



# **Test Procedure:**

- 1. The EUT and support units were located at a ground reference plane with the interposition of a 0.1 m thickness insulating support and the CDN was located on GRP directly.
- 2. Set the testing parameters of CS test software as per IEC/EN 61000-4-6.
- 3. Recorded the test result in following table.

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#### **Test conditions:**

Frequency Range : 0.15MHz-80MHz Frequency Step : 1% of fundamental

Dwell Time : 3 sec

Range (MHz)	Field	Modulation	Result (Pass/Fail)
0.15-80	3V	Yes	Pass

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# **Performance & Result: Criterion A:** The apparatus continues to operate as intended. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance. **Criterion B:** The apparatus continues to operate as intended after the test. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance. During the test, degradation of performance is however allowed. Criterion C: Temporary loss of function is allowed, provided the functions self recoverable or can be restored by the operation of controls. |X PASS **FAIL Observation:** No function degraded during the tests.

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# 15 POWER FREQUENCY MAGNETIC FIELD IMMUNITY TEST

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**Port** : Enclosure

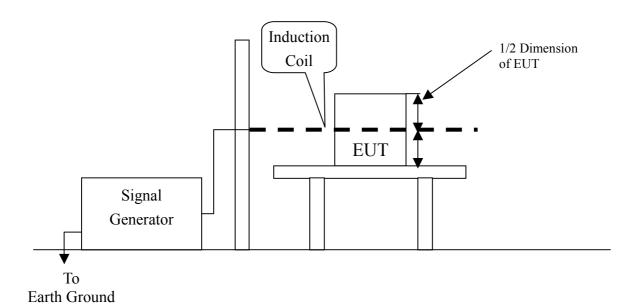
**Basic Standard**: IEC/EN 61000-4-8

**Requirements** : 1 A/m

**Performance Criterion:** A (Standard Required)

Tested by : N/A
Temperature : N/A
Humidity : N/A
Pressure : N/A

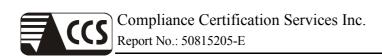
## **Block Diagram of Test Setup:**



# **Test Procedure:**

- 1. The EUT and support units were located on Ground Reference Plane with the interposition of a 0.1 m thickness insulation support.
- 2. Put the induction coil on horizontal direction. ( X direction )
- 3. Recorded the test result as shown in following table.
- 4. Rotated the induction coil by 90° (Y direction) then repeat step 3.
- 5. Rotated the induction coil by 90° ( Z direction ) then repeat step 3.

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### **Test conditions:**

Field Strength: 1A/m Power Freq.: 50Hz Orientation: X, Y, Z

EUT.

Orientation	Field	Result (Pass/Fail)	Remark

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Performance & Result:
Criterion A: The apparatus continues to operate as intended. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance.
Criterion B: The apparatus continues to operate as intended after the test. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance. During the test, degradation of performance is however allowed.
Criterion C: Temporary loss of function is allowed, provided the functions self recoverable or can be restored by the operation of controls.
PASS FAIL
<b>Observation:</b> The EUT is not containing any component that is susceptible to a 50 Hz or 60 Hz magnetic field. Therefore, this requirement is not applicable to the

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### 16 VOLTAGE DIPS / SHORT INTERRUPTIONS

Port : AC Power Port Basic Standard : IEC/EN 61000-4-11

**Requirement**: PHASE ANGLE 0, 45, 90, 135, 180, 225, 270, 315 degrees

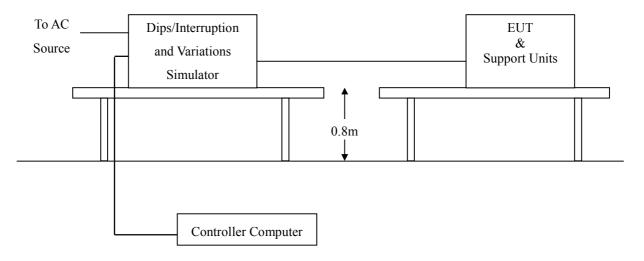
Date of Issue: September 06, 2005

Test Interval : Min. 10 sec.
Tested by : Mark Hsu
Temperature : 22°C
Humidity : 58%
Pressure : 1013mbar

Voltage	Test Level % U <sub>T</sub>	Reduction (%)	Duration ( periods )	Performance Criterion
Dips	<5	>95	0.5	В
	70	30	25	С

Voltage Interruptions	Test Level % U <sub>T</sub>	Reduction (%)	Duration ( periods )	Performance Criterion
Interruptions	<5	>95	250	С

# **Block Diagram of Test Setup:**



### **Test Procedure:**

- 1. The EUT and support units were located on a wooden table, 0.8 m away from ground floor.
- 2. Set the parameter of tests and then Performed the test software of test simulator.
- 3. Changed Condition to occur at 0 degree crossover point of the voltage waveform.
- 4. Recorded the test result in test record form.

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#### **Test conditions:**

The duration with a sequence of three dips/interruptions with interval of 10 sec. minimum (Between each test event)

Date of Issue: September 06, 2005

### **Voltage Dips:**

Test Level % U <sub>T</sub>	Reduction (%)	Duration (periods)	Observation	Meet Performance Criterion	
0	100	0.5	Normal	A	
70	30	25	Normal	A	

#### **Voltage Interruptions:**

Test L	Reduction (%)	Duration (periods)	Observation	Meet Performance Criterion	
0	100	250	EUT shut down, but can be auto recovered as the events disappear.	С	

**Note:** "Normal" means no any functions degrade during and after the test.

### **Performance & Result:**

Criterion A: The apparatus continues to operate as intended. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of

performance.

**Criterion B:** The apparatus continues to operate as intended after the test. No

degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance. During the test, degradation of

performance is however allowed.

**Criterion C:** Temporary loss of function is allowed, provided the functions self

recoverable or can be restored by the operation of controls.

	☐ FAIL
Observation: No function degraded during	g the tests.

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# **APPENDIX I - PHOTOGRAPHS OF TEST SETUP**

# LINE CONDUCTED EMISSION TEST (EN 55022)





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# **COMMON MODE CONDUCTED EMISSION TEST**





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# **RADIATED EMISSION TEST**



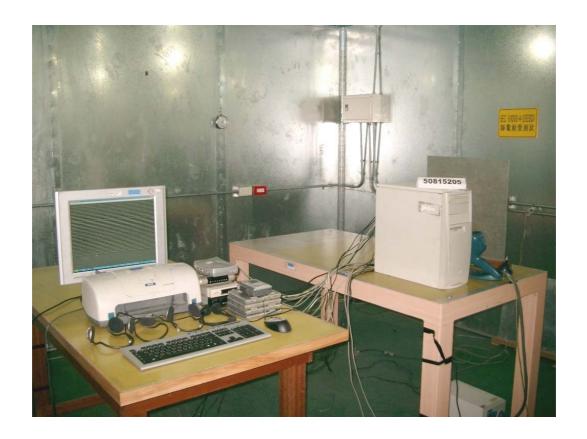


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# POWER HARMONIC & VOLTAGE FLUCTUATION / FLICKER TEST



### ELECTROSTATIC DISCHARGE TEST



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# RADIATED ELECTROMAGNETIC FIELD TEST



# FAST TRANSIENTS/BURST TEST



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# FAST TRANSIENTS/BURST TEST (IEC 61000-4-4 FOR I/O)



### **SURGE IMMUNITY TEST**



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# CONDUCTED DISTURBANCE, INDUCED BY RADIO-FREQUENCY FIELDS TEST



# CONDUCTED DISTURBANCE, INDUCED BY RADIO-FREQUENCY FIELDS TEST (IEC 61000-4-6 FOR I/O)



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# **VOLTAGE DIPS / INTERRUPTION TEST**

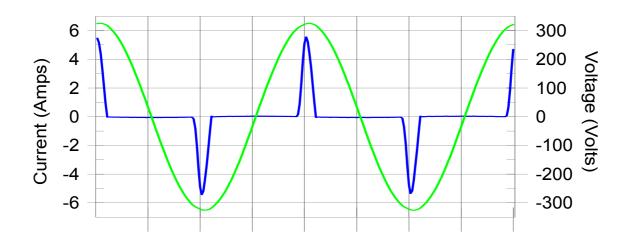


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# APPENDIX II - TEST RESULT OF EN 61000-3-2/-3

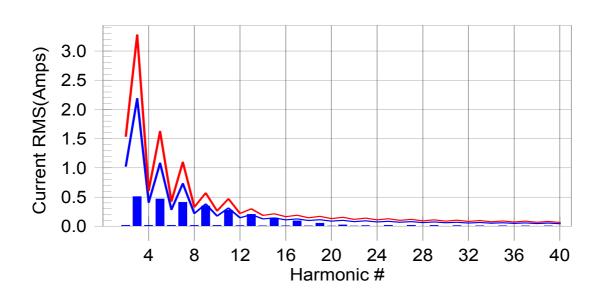
Test Result: Pass Source qualification: Normal

#### **Current & voltage waveforms**



#### **Harmonics and Class A limit line**

#### **European Limits**



Test result: Pass Worst harmonic was #13 with 68.80 % of the limit.

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Test Result: Pass Source qualification: Normal

THC(A): 0.961 I-THD(pk%): 211.983 POHC(A): N/A POHC Limit(A):

N/A

Highest parameter values during test:

**V\_RMS (Volts): 230.03** 

 I\_Peak (Amps):
 5.544
 I\_RMS (Amps):
 1.395

 I\_Fund (Amps):
 0.726
 Crest Factor:
 5.082

 Power (Watts):
 164
 Power Factor:
 0.512

	•	•					
Harm#	Harms(avg)	100%Limit	%of Limit	Harms(max)	150%Limit	%of Limit	Status
2	0.012	1.026	1.1	0.021	1.539	1.33	Pass
3	0.425	2.185	19.5	0.510	3.278	15.56	Pass
4	0.011	0.409	2.8	0.020	0.613	3.28	Pass
5	0.394	1.083	36.4	0.469	1.625	28.90	Pass
6	0.011	0.285	3.9	0.019	0.428	4.49	Pass
7	0.350	0.732	47.9	0.413	1.097	37.68	Pass
8	0.010	0.219	4.7	0.018	0.328	5.37	Pass
9	0.298	0.380	78.4	0.347	0.570	60.89	Pass
10	0.009	0.175	5.3	0.016	0.262	6.01	Pass
11	0.242	0.314	77.1	0.276	0.470	58.70	Pass
12	0.008	0.145	5.6	0.014	0.219	6.22	Pass
13	0.185	0.200	92.8	0.206	0.299	68.80	Pass
14	0.007	0.124	5.6	0.011	0.187	6.06	Pass
15	0.132	0.143	92.9	0.142	0.214	66.39	Pass
16	0.006	0.109	5.2	0.009	0.164	5.62	Pass
17	0.086	0.125	68.8	0.093	0.189	49.34	Pass
18	0.004	0.097	4.6	0.007	0.145	4.95	Pass
19	0.049	0.112	43.4	0.054	0.169	31.84	Pass
20	0.003	0.087	3.8	0.005	0.131	4.15	Pass
21	0.021	0.102	20.9	0.024	0.153	15.62	Pass
22	0.002	0.079	3.0	0.004	0.119	3.40	Pass
23	0.005	0.093	5.9	0.012	0.140	8.79	Pass
24	0.002	0.073	2.2	0.003	0.109	2.96	Pass
25	0.015	0.086	17.5	0.020	0.128	15.27	Pass
26	0.001	0.067	1.7	0.003	0.101	2.65	Pass
27	0.018	0.079	22.9	0.020	0.119	17.20	Pass
28	0.001	0.063	1.3	0.002	0.094	2.43	Pass
29	0.017	0.074	22.7	0.017	0.110	15.82	Pass
30	0.001	0.058	1.1	0.002	0.087	2.28	Pass
31	0.013	0.069	19.0	0.014	0.104	13.74	Pass
32	0.001	0.055	1.0	0.002	0.082	2.15	Pass
33	0.010	0.065	15.0	0.011	0.097	11.21	Pass
34	0.000	0.051	1.0	0.002	0.077	2.06	Pass
35	0.008	0.061	12.6	0.009	0.091	9.77	Pass
36	0.001	0.049	1.1	0.002	0.073	2.06	Pass
37	0.007	0.058	12.4	0.008	0.086	9.43	Pass
38	0.001	0.046	1.2	0.001	0.069	2.13	Pass
39	0.007	0.055	12.7	0.008	0.083	9.50	Pass
40	0.001	0.044	1.2	0.001	0.066	2.14	Pass

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Test Result: Pass Source qualification: Normal

#### Highest parameter values during test:

Voltage (Vrms): 230.03

 I\_Peak (Amps):
 5.544
 I\_RMS (Amps):
 1.395

 I\_Fund (Amps):
 0.726
 Crest Factor:
 5.082

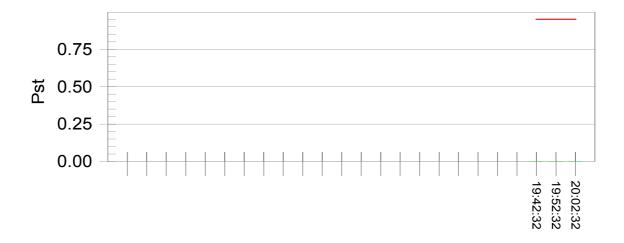
 Power (Watts):
 164
 Power Factor:
 0.512

Harm#	Harmonics V-rms	Limit V-rms	% of Limit	Status
2	0.124	0.460	27.03	ОК
3	0.471	2.069	22.75	ОК
4	0.052	0.460	11.23	OK
5	0.129	0.919	14.04	ОК
6	0.034	0.460	7.30	OK
7	0.204	0.690	29.61	OK
8	0.033	0.460	7.10	OK
9	0.151	0.460	32.88	OK
10	0.016	0.460	3.40	OK
11	0.164	0.230	71.18	OK
12	0.025	0.230	10.68	OK
13	0.142	0.230	61.71	OK
14	0.014	0.230	6.21	OK
15	0.113	0.230	49.01	OK
16	0.016	0.230	7.06	OK
17	0.086	0.230	37.18	OK
18	0.022	0.230	9.76	OK
19	0.053	0.230	23.20	OK
20	0.016	0.230	6.93	OK
21	0.030	0.230	13.09	OK
22	0.021	0.230	9.12	OK
23	0.070	0.230	30.47	OK
24	0.019	0.230	8.48	OK
25	0.043	0.230	18.68	OK
26	0.019	0.230	8.44	OK
27	0.041	0.230	17.76	OK
28	0.011	0.230	4.99	OK
29	0.035	0.230	15.32	OK
30	0.017	0.230	7.57	OK
31	0.027	0.230	11.60	OK
32	0.012	0.230	5.06	OK
33	0.015	0.230	6.44	OK
34	0.007	0.230	3.16	OK
35	0.032	0.230	14.02	OK
36	0.007	0.230	2.91	OK
37	0.019	0.230	8.47	OK
38	0.005	0.230	2.22	OK
39	0.014	0.230	5.94	OK
40	0.007	0.230	3.25	ok

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Test Result: Pass Status: Test Completed

### Pst<sub>i</sub> and limit line European Limits



### Time is too short for Plt plot

### Parameter values recorded during the test:

Vrms at the end of test (Volt):	229.35			
Highest dt (%):	0.00	Test limit (%):	3.14	Pass
Time(mS) > dt:	0.0	Test limit (mS):	500.0	Pass
Highest dc (%):	0.00	Test limit (%):	3.14	Pass
Highest dmax (%):	0.00	Test limit (%):	3.80	Pass
Highest Pst (10 min. period):	0.001	Test limit:	0.950	Pass
Highest Plt (2 hr. period):	0.001	Test limit:	0.617	Pass

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# **APPENDIX III - TEST RESULT OF FINAL DATAS**

**Conducted Emission Plot** 

Date of Issue: September 06, 2005

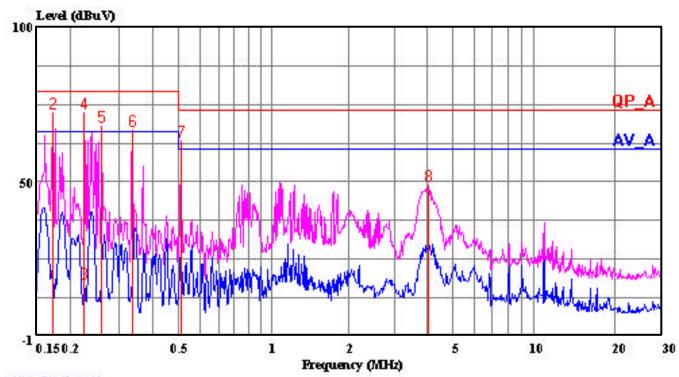
**Radiated Emission Data** 

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Tel:02-2217-0894 Fax:02-2217-1029

Data#: 19 File#: 50815205CA.EMI Date: 2005-08-31 Time: 15:20:03



(Conduction A)

Trace: 2 1 Ref Trace:

Condition: LINE

Report No. : 50815205 Test Engr. : SAM SU

Company : AAEON Technology Inc.

EUT : EMB-900M

Test Config : EUT / ALL PERIPHERALS Type of Test: EN 55022 CLASS A Mode of Op. : DVI TO D-SUB MODE

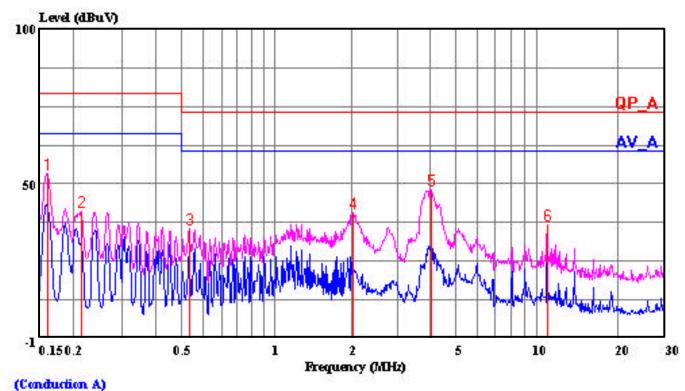
Page:	1	
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	Freq	Read Level	Factor	Level	Limit Line	Over Limit	Remark
	MHz	dBuV	dB	dBuV	dBuV	dB	
1 2 3 4 5 6	0.171 0.171 0.224 0.224 0.260 0.337 0.510	15.45 72.03 16.37 72.03 67.29 66.15 62.48	0.14 0.14 0.15 0.15 0.17 0.19	15.59 72.17 16.52 72.18 67.46 66.34 62.68	79.00 66.00 79.00 79.00 79.00	-6.83 -49.48	Average Peak Peak Peak
8	4.158	47.86	0.20	48.21		-10.32 $-24.79$	



Tel:02-2217-0894 Fax:02-2217-1029

Data#: 20 File#: 50815205CA.EMI Date: 2005-08-31 Time: 15:20:53



Trace: 4 3 Ref Trace:

Condition: NEUTRAL
Report No. : 50815205
Test Engr. : SAM SU

Company : AAEON Technology Inc.

EUT : EMB-900M

Test Config : EUT / ALL PERIPHERALS Type of Test: EN 55022 CLASS A Mode of Op. : DVI TO D-SUB MODE

	Page:	1
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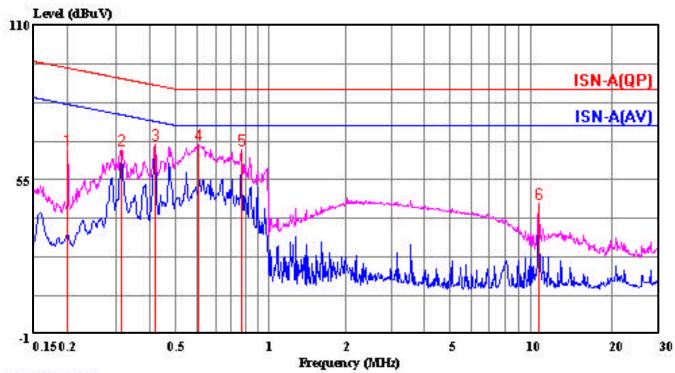
		Read			Limit	Over	
	Freq	Level	Factor	Level	Line	Limit	Remark
	MHz	dBuV	dВ	dBuV	dBuV	dB	
1	0.160	52.59	0.13	52.72	79.00	-26.28	Peak
2	0.213	40.41	0.13	40.54	79.00	-38.46	Peak
3	0.532	34.79	0.21	35.00	73.00	-38.00	Peak
4	2.133	39.78	0.32	40.10	73.00	-32.90	Peak
5	4.158	46.97	0.40	47.37	73.00	-25.63	Peak
6	11.080	35.16	0.98	36.14	73.00	-36.86	Peak



Page: 1

Tel:02-2217-0894 Fax:02-2217-1029

Data#: 21 File#: 50815205CA.EMI Date: 2005-08-31 Time: 15:24:45



(Conduction A)

Trace: 10 9 Ref Trace:

Condition: COMMON MODE Report No. : 50815205 Test Engr. : SAM SU

: AAEON Technology Inc. Company

: EMB-900M EUT

Test Config : EUT / ALL PERIPHERALS Type of Test: EN 55022 CLASS A

Mode of Op. : LAN 2 / 1 Gbps / WORST

	Freq	Read Level	Factor	Level	Limit Line	Over Limit	Remark
	MHz	dBuV	dB	dBuV	dBuV	dB	
1	0.201	55.43	9.77	65.20	94.58	-29.38	Peak
2	0.315	55.40	9.75	65.15	90.84	-25.69	Peak
3	0.419	57.44	9.75	67.19	88.46	-21.28	Peak
4	0.608	57.43	9.74	67.17	87.00	-19.83	Peak
5	0.871	55.65	9.74	65.39	87.00	-21.61	Peak
6	10.790	36.17	9.80	45.97	87.00	-41.03	Peak



Tel:02-2217-0894 Fax:02-2217-1029

Data#: 1 File#: 50815205-I.EMI Date: 2005-08-17 Time: 16:09:58

Site#I

Condition: VERTICAL /10M Report No. : 50815205 Test Engr. : JIMMY CHEN

Company : AAEON Technology Inc.

EUT : EMB-900M

Test Config : EUT / ALL PERIPHERALS

Type of Test: EN 55022 CLASS A Mode of Op. : DVI TO D-SUB MODE

Page: 1

		Read			Limit	Over	
	Freq	Level	Factor	Level	Line	Limit	Remark
	MHz	dBuV	dB	dBuV/m	dBuV/m	dB	
1	37.770	49.53	-19.87	29.66	40.00	-10.34	Peak
2	45.640	45.64	-24.07	21.57	40.00	-18.43	Peak
3	56.650	52.89	-26.60	26.29	40.00	-13.71	Peak
4	66.100	63.64	-26.89	36.75	40.00	-3.25	Peak
5	75.530	61.24	-25.90	35.34	40.00	-4.66	Peak
6	120.070	46.19	-19.84	26.35	40.00	-13.65	Peak
7	122.750	53.25	-19.83	33.42	40.00	-6.58	Peak
8	125.110	49.66	-19.91	29.76	40.00	-10.25	Peak
9	166.000	56.96	-21.22	35.74	40.00	-4.26	Peak
10	169.930	47.23	-21.36	25.88	40.00	-14.13	Peak
11	207.700	52.59	-20.90	31.69	40.00	-8.31	Peak
12	233.380	51.16	-18.86	32.30	47.00	-14.70	Peak
13	250.020	43.06	-17.53	25.53	47.00	-21.47	Peak
14	400.020	45.32	-12.76	32.56	47.00	-14.44	Peak
15	432.080	40.27	-11.75	28.52	47.00	-18.48	Peak
16	480.020	40.96	-10.46	30.50	47.00	-16.50	Peak



Tel:02-2217-0894 Fax:02-2217-1029

Date: 2005-08-17 Time: 16:37:34 Data#: 2 File#: 50815205-I.EMI

Site#I

Condition: HORIZONTAL Report No. : 50815205 Test Engr. : JIMMY CHEN

Company : AAEON Technology Inc.

EUT : EMB-900M

Test Config : EUT / ALL PERIPHERALS

Type of Test: EN 55022 CLASS A Mode of Op. : DVI TO D-SUB MODE

Page: 1

		Read			Limit	Over	
	Freq	Level	Factor	Level	Line	Limit	Remark
	MHz	dBuV	dB	dBuV/m	dBuV/m	dB	
1	56.650	48.66	-26.60	22.06	40.00	-17.94	Peak
2	56.650	53.21	-26.60	26.61	40.00	-13.39	Peak
3	66.090	55.69	-26.89	28.80	40.00	-11.20	Peak
4	75.530	56.36	-25.90	30.46	40.00	-9.54	Peak
5	113.310	46.12	-20.28	25.84	40.00	-14.16	Peak
6	122.740	54.34	-19.83	34.51	40.00	-5.49	Peak
7	169.930	47.36	-21.36	26.01	40.00	-14.00	Peak
8	207.720	50.26	-20.90	29.36	40.00	-10.64	Peak
9	233.380	51.40	-18.86	32.54	47.00	-14.46	Peak
10	250.030	47.82	-17.53	30.29	47.00	-16.71	Peak
11	300.030	43.27	-16.09	27.18	47.00	-19.82	Peak
12	400.050	42.44	-12.76	29.68	47.00	-17.32	Peak
13	480.070	45.26	-10.46	34.80	47.00	-12.20	Peak
14	500.060	48.32	-9.96	38.36	47.00	-8.64	Peak